



PRODUCT DATA SHEET



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Datasheet



Resources



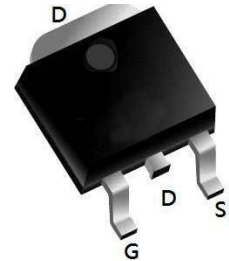
Samples

Please note: Please check the JINGAO Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.jg-semi.cn. Please email any questions regarding the system integration to JINGAO_questions@jgsemi.com.

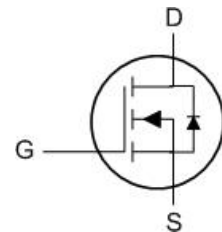
BVDSS	RDSON	ID
30V	2.8mΩ	100A

- ★ Super Low Gate Charge
- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench

technology



TO252-3L



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	100	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	60	A
I_{DM}	Pulsed Drain Current ²	480	A
EAS	Single Pulse Avalanche Energy ³	256	mJ
I_{AS}	Avalanche Current	---	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	75	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	---	---	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	2	$^\circ C/W$

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	H0	---	---	V
ΔBV _{DSS} /ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C, I _D =1mA	---	---	---	V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =F€V, I _D =4.5A	---	G€	H€	mΩ
		V _{GS} =I.5V, I _D =3.5A	---	I €H	í €	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	F	F€	G€	V
ΔV _{GS(th)}	V _{GS(th)} Temperature Coefficient		---	---	---	mV/°C
I _{DSS}	Drain-Source Leakage Current	V _{DS} =H0V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =H0V, V _{GS} =0V, T _J =100°C	---	---	100	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±G€V, V _{DS} =0V	---	---	±100	nA
g _{fs}	Forward Transconductance	V _{DS} =5V, I _D =G€A	---	G €G	---	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	F€	---	Ω
Q _g	Total Gate Charge	V _{DS} =Fí V, V _{GS} =F€V, I _D =G€A	---	I ì	---	nC
Q _{gs}	Gate-Source Charge		---	í €G	---	
Q _{gd}	Gate-Drain Charge		---	J €	---	
T _{d(on)}	Turn-On Delay Time	V _{GS} =F€V, V _{DD} =1í V, R _G =H0, I _D =G€A	---	F I €	---	ns
T _r	Rise Time		---	H í	---	
T _{d(off)}	Turn-Off Delay Time		---	I H €	---	
T _f	Fall Time		---	G G	---	
C _{iss}	Input Capacitance	V _{DS} =1í V, V _{GS} =0V, f=1MHz	---	G í I	---	pF
C _{oss}	Output Capacitance		---	G J	---	
C _{rss}	Reverse Transfer Capacitance		---	G í	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current ^{1,4}	V _G =V _D =0V, Force Current	---	---	100	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =1A, T _J =25C	---	---	1.2	V
t _{rr}	Reverse Recovery Time	I _F =G€A, di/dt=100A/μs,	---	í î	---	nS
Q _{rr}	Reverse Recovery Charge	T _J =25 C	---	I G	---	nC

Note :

F€ The data is tested by surface mounted on 4 inch² FR-4 board with 20Z copper.

G€ The data is tested by pulsed pulse width ≤ 300us, duty cycle ≤ 2%

Hí The EAS data shows Max. Rating At the test condition As A/RMG ×0, VDD=30V, V_G=10V, R_G=25Ω, L=0.5mH

I € The power dissipation is limited by 150°C junction temperature

í € The data is theoretically the same as A_D and A_{DMA}. In real applications, it should be limited by total power dissipation.

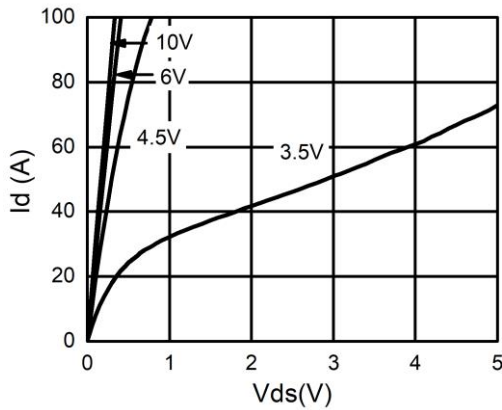
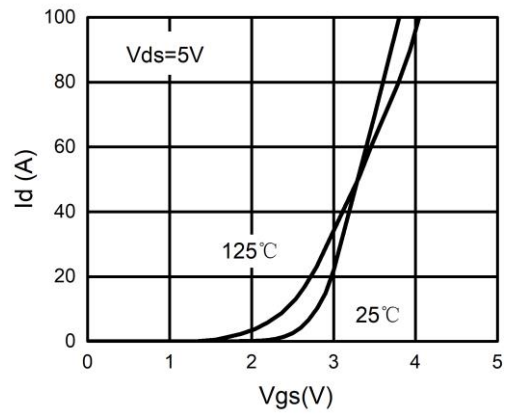
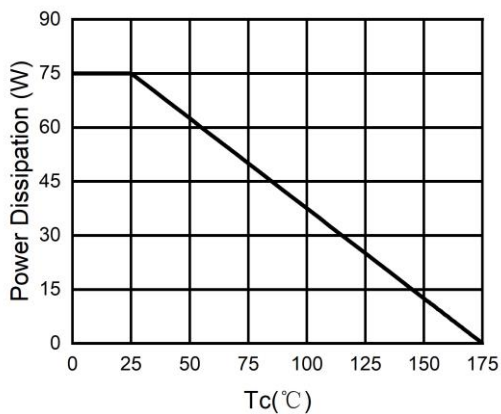
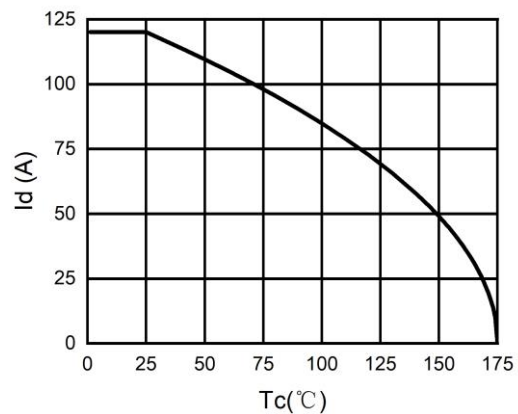
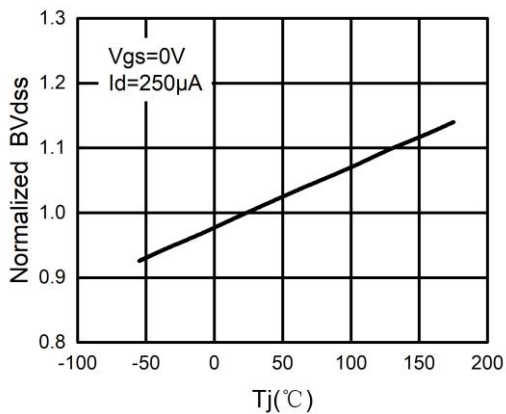
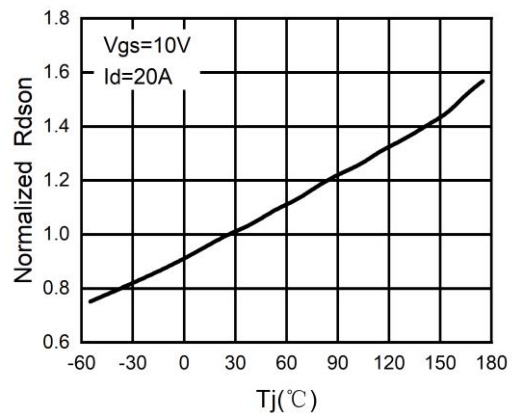
Typical Electrical And Thermal Characteristics (Curves)
Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

Figure 3. Power Dissipation

Figure 4. Drain Current

Figure 5. BV_{DSS} vs Junction Temperature

Figure 6. $R_{DS(ON)}$ vs Junction Temperature


Figure 7. Gate Charge Waveforms

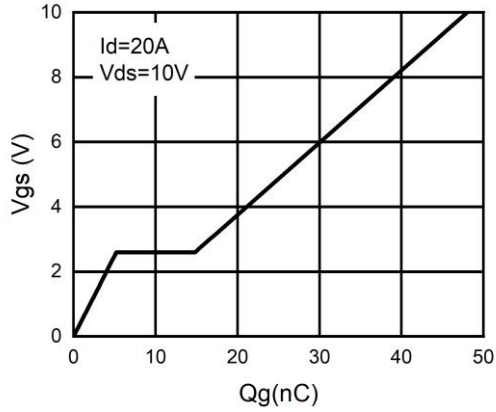


Figure 8. Capacitance

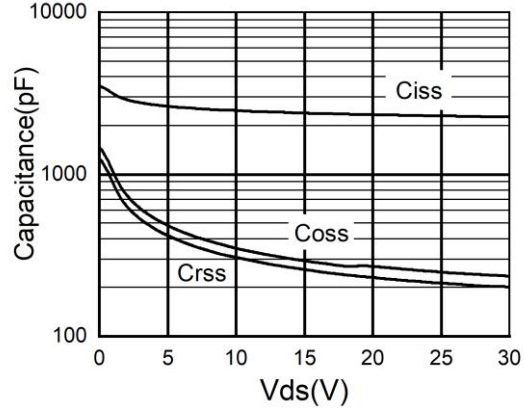


Figure 9. Body-Diode Characteristics

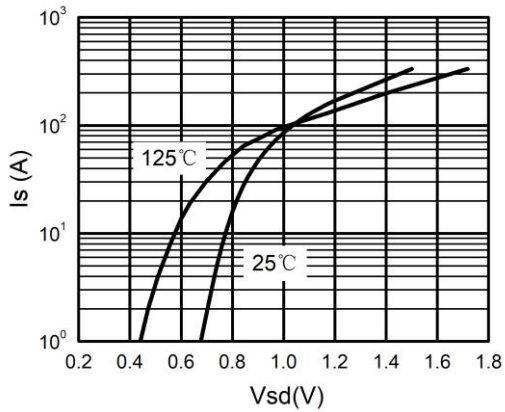
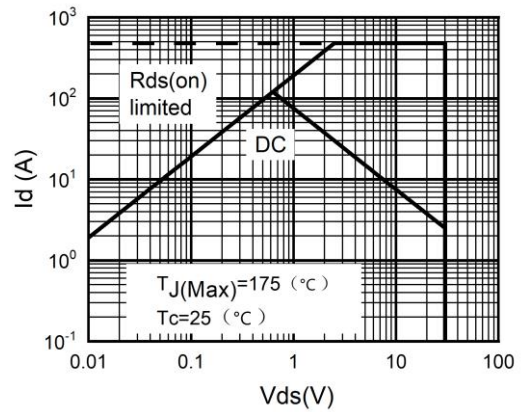
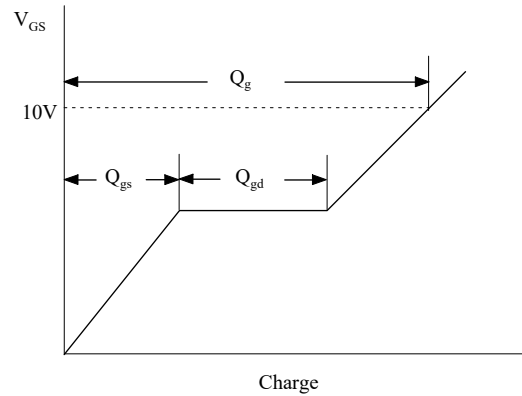
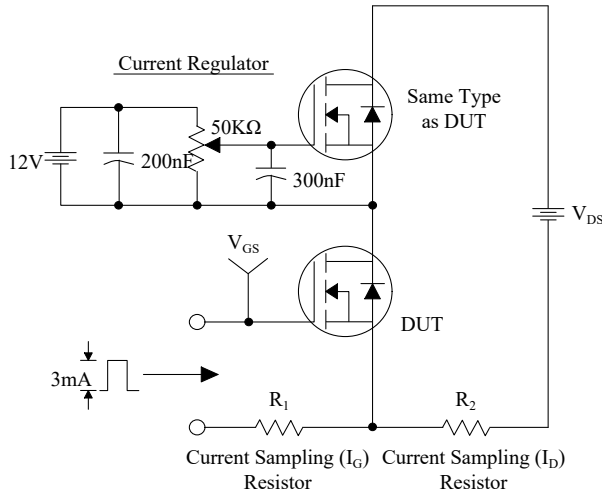


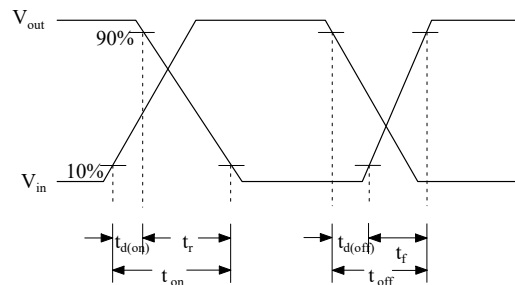
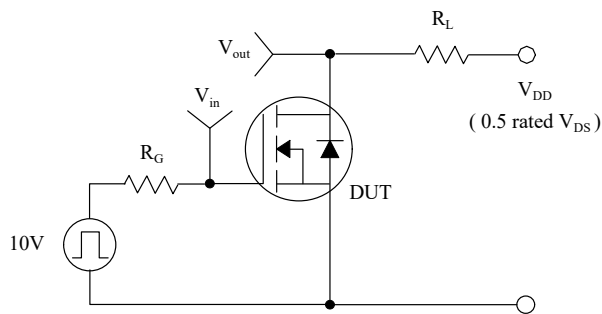
Figure 10. Maximum Safe Operating Area



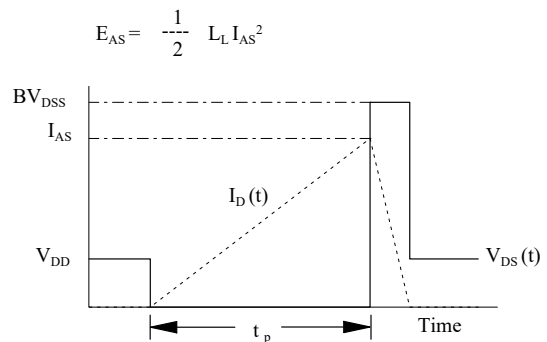
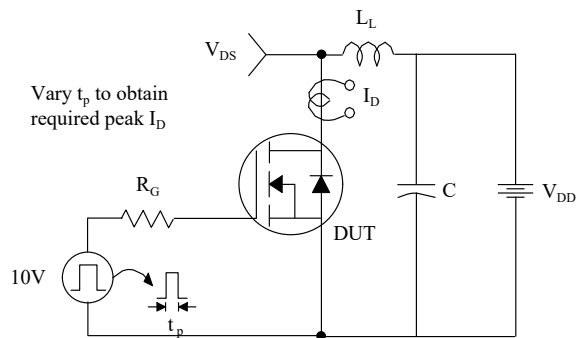
Gate Charge Test Circuit & Waveform

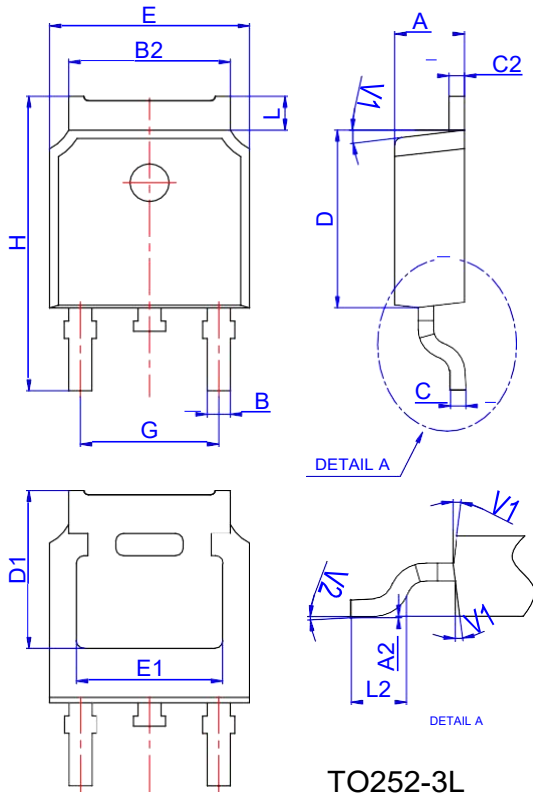


Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Package Mechanical Data TO252-3L

TO252-3L

Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

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